

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Application No.	Unknown <b>10/561830</b>
	Filing Date	Herewith
	First Named Inventor	Hayashi, Ryotaro
	Art Unit	Unknown <b>2752 DEC 2005</b>
(Multiple sheets used when necessary)		Examiner
SHEET 1 OF 1		Attorney Docket No. SHIGA7.040APC

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
/P.T.R./	1	US 2003/0203309 A1	10-30-2003	Nishimura et al.	
/P.T.R./	2	US 2002/0132181 A1	09-19-2002	Nishimura et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>
/P.T.R./	3	JP 2003-84436	03-19-2003			
/P.T.R./	4	JP 2003-173026	06-20-2003			
/P.T.R./	5	JP 2002-311590	10-23-2002			
/P.T.R./	6	JP 2003-167347	06-13-2003			
/P.T.R./	7	JP 2003-337419	11-28-2003			
/P.T.R./	8	JP 2003-337417	11-28-2003			
/P.T.R./	9	JP 2003-280201	10-02-2003			
/P.T.R./	10	JP 2003-246825	09-05-2003			
/P.T.R./	11	JP 2881969	02-05-1999	Fujitsu Ltd.		Abstract
/P.T.R./	12	JP 05-346668	12-27-1993	Fujitsu Ltd.		X
/P.T.R./	13	JP 07-234511	09-05-1995	Fujitsu Ltd.		X
/P.T.R./	14	JP 09-073173	03-18-1997	Fujitsu Ltd.		X
/P.T.R./	15	JP 09-090837	04-04-1997	Fujitsu Ltd.		X
/P.T.R./	16	JP 10-161313	06-19-1998	Fujitsu Ltd.		X
/P.T.R./	17	JP 10-319595	12-04-1998	Fujitsu Ltd.		X
/P.T.R./	18	JP 11-012328	01-19-1999	Fujitsu Ltd.		X

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>

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T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.

<b>Notice of References Cited</b>	Application/Control No. 10/561,830	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
	Examiner Ponder N. Thompson-Rummel	Art Unit 1753	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0110085	06-2004	Iwai et al.	430/270.1
*	B	US-2004/0029037	02-2004	Kamabuchi et al.	430/270.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003167347 A	06-2003	Japan	HANEDA et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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